

Search Notes 	Application/Control No. 10/773,640	Applicant(s)/Patent under Reexamination CHEN ET AL.
	Examiner Syed Zaidi	Art Unit 2616

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
AST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12/28/2007	SZ
Inventor :CHEN ET AL.	12/28/2007	SZ
IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	12/28/2007	SZ
(370/466 370/465 370/464 370/280 370/281 370/298).CCLS.	12/28/2007	SZ
Consulted with SPE Seema S. Rao	12/28/2007	SZ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner